

Hierarchical identification of NBTI-critical gates in nanoscale logic

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Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; Tihomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Identifying NBTI-critical paths in nanoscale logic

Ubar, Raimund-Johannes; Vargas, Fabian; Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei; Bolzani Poehls, Leticia 16th Euromicro Conference series on Digital System Design : DSD 2013 : proceedings : 4-6 September 2013, Santander, Spain 2013 / p. 136-141 : ill

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill
<http://dx.doi.org/10.1109/LATW.2015.7102405>

SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic

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